

**Notice of References Cited**

Application/Control No.

10/500,511

Applicant(s)/Patent Under  
Reexamination  
BADYLAK ET AL.

Examiner

Shin-Lin Chen

Art Unit

1632

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,175,841	02-2007	Badylak et al.	424/93.7
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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